


Search Notes 	Application/Control No. 10526715	Applicant(s)/Patent Under Reexamination KEMPF, JURGEN
	Examiner SHEELA C CHAWAN	Art Unit 2624

SEARCHED

Class	Subclass	Date	Examiner
382	100, 124, 184, 119, 311, 115, 181, 187, 309	7/5/09	SCC
713	180, 186, 176, 193, 180, 182, 194, 189, 150, 168,	"	"
401	195	"	"
178	19.01, 18.09, 18.03, 18.01	"	"
705	76	"	"
340	5.1, 5.2, 825, 5.4, 5.52, 5.51	"	"
235	386, 375	"	"
345	179, 156	"	"
346	139 R	"	"
726	34	"	"
382	115, 119	1/17/10	SCC
713	186	1/17/10	SCC
340	5.52	1/17/10	SCC
178	19.01	1/17/10	SCC
SEARCH UP-DATE		1/17/10	SCC

SEARCH NOTES

Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	7/5/09	SCC
SEARCH INVENTORE .	"	"
SEARCH EAST AND OTHER DATA BASE SEE THE SEARCH HISTORY.	1/18/10	SCC
713/186, 176, 193, 180, 182, 194, 186, 189, 150, 168.CCLS. US.PATENT TEXT SEARCH.	1/18/10	SCC
382/100, 124, 184, 119, 311, 115, 181, 187, 309.CCLS. US-PATENT TEXT SEARCH.	1/18/10	SCC
340/825.5.1, 5.4, 5.2, 5.52, 5.51.CCLS. US.PATENT TEXT SEARCH.	1/18/10	SCC
178/19.01, 18.09, 18.01, 18.03.CCLS. US.PATENT TEXT SEARCH.	1/18/10	SCC
INTERFERENCE SEARCH	1/18/10	SCC
SEARCH IEEE OR INSPEC DATA BASE.	1/18/10	SCC
SEARCH UP-DATE	1/18/10	SCC

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INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
382	115,119	1/18/10	SCC
713	186	1/18/10	SCC
340	5.52	1/18/10	SCC
178	19.01	1/18/10	SCC

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